

SID4 NIR (1.55 μm)

WAVE FRONT SENSOR



PHASICS introduces his **high resolution wave front sensor** for near IR region (from 1.5 μm to 1.6 μm).

For **laser beam metrology**, the SID4 NIR gives an exhaustive beam characterization (aberrations, M^2 , intensity profiles, beam parameters).

For **optical metrology**, the SID4 NIR is the perfect tool to characterize IR objectives or IR lenses giving you aberrations, PSF, MTF, focal length and analyzing surface quality.

The ease of use and compactness make the SID4 NIR very simple to integrate.

This document is not contractual.

➤ SPECIFICATIONS

Aperture dimension	3.6 x 4.8 mm ²
Spatial resolution	29.6 μm
Sampling	160 x 120
Wavelength range	1.5 μm – 1.6 μm
Accuracy	15 nm RMS
Sensitivity	11 nm RMS
Dynamic	> 100 μm
Analysis rate	> 10 fps
Acquisition rate	60 fps
Dimensions (l x H x L)	44 x 33 x 57.5 mm
Weight	250 g

➤ KEY FEATURES

- High resolution (160 x 120)
- Phase map interpretation modules
- Intensity profile characterization
- Absolute measurement
- Fast measurement
- Insensitive to vibration
- Cost effective



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